

S-Range Stage Micrometers

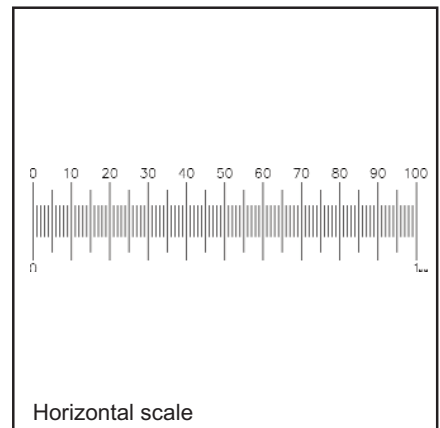
These stage graticules are intended for the routine calibration of eyepiece reticles particularly when alternating between objectives on one microscope or when using the same reticle in different microscopes.

Their robust construction, with metal slide mount, makes them ideal for student use and for instructional purposes. The scale or grid is centred on a glass disc mounted in a black anodised aluminium slide 76mm x 25mm x 1mm thick. The image is created using vacuum deposited chrome which is resistant to normal wear and tear.

Versions are available for transmitted light and reflected (incident) light

Accuracy and Line Widths of Stage Micrometers

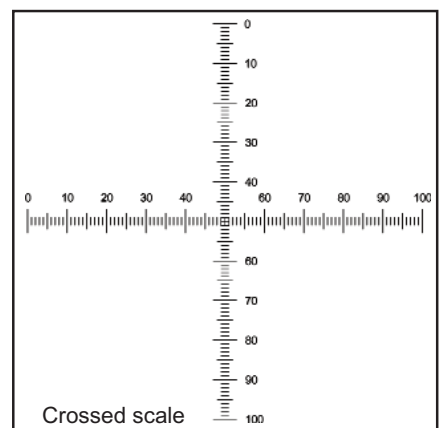
Pattern	Line Width	Accuracy (overall)
S1	0.005mm	Within 0.002mm
S2	0.005mm	Within 0.015mm
S4	0.002mm	Within 0.0001 inch
S8	0.002mm	Within 0.0015mm
S11	0.001mm	Within 0.00005 inch
S12	0.001mm	Within 0.001mm
S16	0.0015mm	Within 0.0015mm
S22	0.0025mm	Within 0.0015mm
S48	0.0027mm	Within 0.0015mm
S78	0.003mm	Within 0.001mm
S20	0.0025mm	Within 0.0015mm
S21	0.0025mm	Within 0.0015mm
S9	0.005mm	Within 0.0015mm
S10	0.004mm	Within 0.0015mm
S28	0.004mm	Within 0.0015mm
S29	0.0025mm	Within 0.0015mm
S1R	0.005mm	Within 0.002mm
S4R	0.002mm	Within 0.0001 inch



For Transmitted Light

Horizontal micrometer scales and crossed micrometer scales.

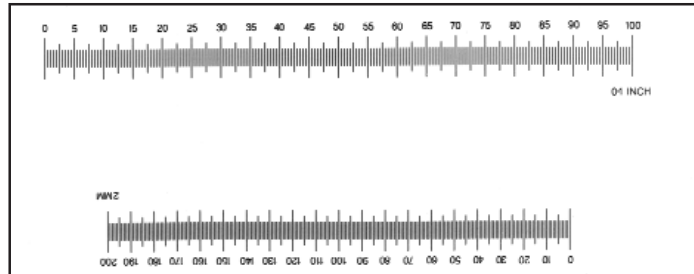
Pattern	Description	Order Code
S1	Micrometer scale 10mm in 0.1mm divisions	02A00400
S2	Micrometer scale 5mm in 0.05mm divisions	02A00401
S4	Micrometer scale 0.1inch in 0.001inch divisions	02A00402
S8	Micrometer scale 1mm in 0.01mm divisions	02A00404
S11	Micrometer scale 0.005inch in 0.0001inch divisions	02A00407
S12	Micrometer scale 0.1mm in 0.002mm divisions	02A00408
S16	Crossed micrometer scales 1mm in 0.01mm divisions	02A00429
S22	Micrometer scale vertical 2mm in 0.01mm divisions	02A00411
S48	Micrometer scale 1mm in 0.01mm divisions, no coverglass	02A00414



Combined Metric/Imperial Scales

Pattern	Description	Order Code
S20	Double micrometer scale 2mm in 0.01mm divisions and 0.1inch in 0.0005inch divisions	02A00409

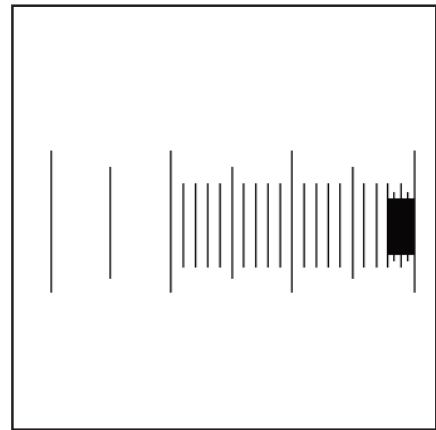
See also PS52



Grouped Graduation Scale

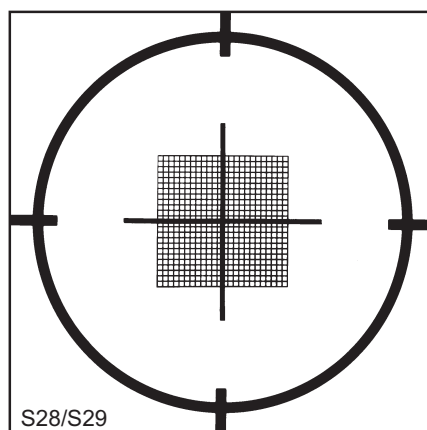
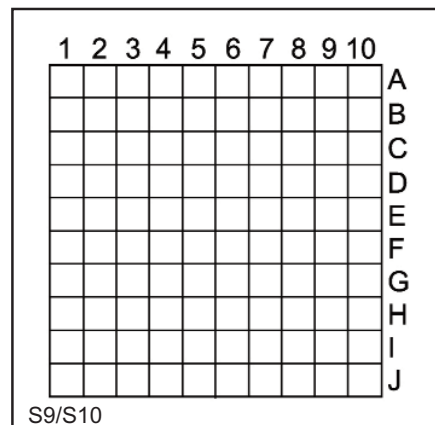
For speedy determination of a range of feature sizes within a given specimen.

Pattern	Description	Order Code
S21	Micrometer scale 5mm in 0.5mm divisions, 2mm in 0.1mm divisions, and 0.2mm in 0.01mm divisions	02A00410



Grids

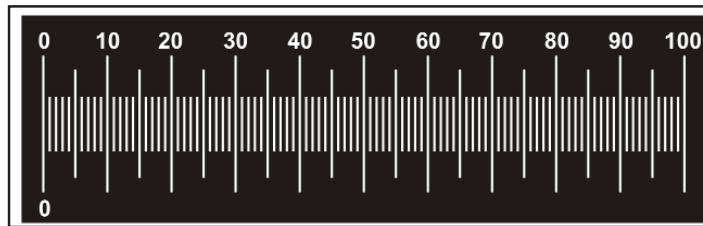
Pattern	Description	Order Code
S9	Counting slide 0.1mm squares.	02A00405
S10	Counting slide 0.05mm squares.	02A00406
S28	0.01mm grid / 0.2 x 0.2mm overall.	02B00428
S29	0.01mm grid / 1.5 x 1.5mm overall.	02B00429



For Reflected Light

These scales are etched through highly reflective vacuum coated metal. When viewed under vertical illumination, as with a metallurgical microscope, the scale appears black against a bright background.

Pattern	Description	Order Code
S78	Micrometer scale 1mm in 0.01mm divisions,	02B00421
S1R	Micrometer scale 10mm in 0.1mm divisions,	02A00440
S4R	Micrometer scale 0.1" in 0.001" divisions,	02A00442



Diamond Ruled Stage Micrometer

Stage micrometers with very fine well defined lines are available from Pyser-SGI. These reference scales offer substantial improvements in definition over the standard types when used under the highest magnification. This is made possible by the use of diamond cutting tools and a special ruling engine

The S91 has clear lines ruled through a semi-opaque metal film which, with transmitted light, appear as bright lines on a dark background.

The micrometer is made on a glass substrate 76mm x 26mm x 1.2mm thick. The lines are 1 micron wide or less and 3.5mm long, The metric rulings provide a scale of 1mm divided into 0.1mm parts, with one part being sub-divided into 0.01mm parts.

Pattern	Description	Order Code
S91	Diamond ruled stage micrometer	02D00481



Particle Analysis Test Slide

SG7

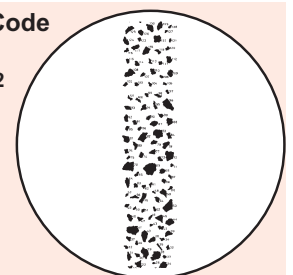
Ideal for staff training, this has 100 particles of various shapes and sizes. Each shape is numbered. Designed for comparing various shapes and sizes, and as a means for logging and communicating this information.

Pattern Description

SG7 Test slide for particle sizing.

Order Code

02A00422



H.S.E./N.P.L. MKIII Test Slide for Phase Contrast Microscopy

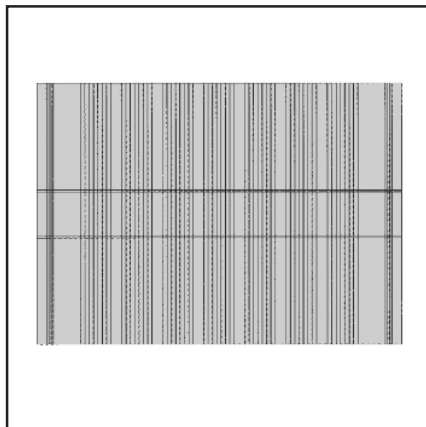
This test slide is made in the UK under licence from the National Physical Laboratory.

It is an epoxy replica of a master slide produced and certified by that laboratory. The replicas are mounted on microscope slides of 1.2 mm thickness with cover glass of 0.17 mm thickness.

The purpose of the slide is to provide a standard means to check the performance of phase microscopes prior to the analysis of asbestos. The pattern consists of seven bands of twenty lines with widths ranging from 0.25 μ m to 1.1 μ m.

A satisfactory system will detect block 5. Full details are supplied with the slide.

Pattern	Description	Order Code	Block No.	Ridge Width (Micrometers)	Maximum Calculated Phase Change (in degrees) for light rays (wavelength = 530 nanometers) passing through test objects.
S84	HSE Test slide for calibration in asbestos analysis	02F00490			
			1	1.08	6.6
			2	0.77	4.7
			3	0.64	3.9
			4	0.53	3.2
			5	0.44	2.7
			6	0.36	2.2
			7	0.25	1.5



Vibration (FOE PPL Dot)

The amount of vibration of the slide in the appropriate axis is determined by the pair of dots which appear to merge into a single dot.

The pattern on the S25 is an array of 20 pairs of dots converging on a single dot. The distance between each dot pair increases by 0.001 inch to a maximum of 0.02 inches, pairs being equispaced 0.25 inch. Supplied on 76 x 26mm glass slide.

Pattern	Description	Order Code
S25	FOE PPL Dot vibration test pattern	02A00412

